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**Visokonapetostne preskusne tehnike - Meritve delnih razelektritev - Dopolnilo A1**

High-voltage test techniques - Partial discharge measurements

Hochspannungs-Prüftechnik - Teilentladungsmessungen

Techniques des essais à haute tension - Mesures des décharges partielles

**Ta slovenski standard je istoveten z: EN 60270:2001/A1:2016**[SIST EN 60270:2002/A1:2016](https://standards.iteh.ai/catalog/standards/sist/ad541ddd-9cdc-4af1-b46c-9da9fd4cfd9/sist-en-60270-2002-a1-2016)<https://standards.iteh.ai/catalog/standards/sist/ad541ddd-9cdc-4af1-b46c-9da9fd4cfd9/sist-en-60270-2002-a1-2016>**ICS:**

17.220.20	Merjenje električnih in magnetnih veličin	Measurement of electrical and magnetic quantities
19.080	Električno in elektronsko preskušanje	Electrical and electronic testing

**SIST EN 60270:2002/A1:2016****en**

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EUROPEAN STANDARD

EN 60270:2001/A1

NORME EUROPÉENNE

EUROPÄISCHE NORM

March 2016

ICS 17.220.20; 19.080

English Version

## High-voltage test techniques - Partial discharge measurements (IEC 60270:2000/A1:2015)

Techniques des essais à haute tension - Mesures des  
décharges partielles  
(IEC 60270:2000/A1:2015)

Hochspannungs-Prüftechnik - Teilentladungsmessungen  
(IEC 60270:2000/A1:2015)

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Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

**EN 60270:2001/A1:2016****European foreword**

The text of document 42/338/FDIS, future IEC 60270:2000/A1, prepared by IEC/TC 42 "High-voltage testing techniques" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 60270:2001/A1:2016.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2016-10-01
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2019-01-01

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# INTERNATIONAL STANDARD

# NORME INTERNATIONALE



AMENDMENT 1  
AMENDEMENT 1

High-voltage test techniques – Partial discharge measurements

Techniques des essais à haute tension – Mesures des décharges partielles

[SIST EN 60270:2002/A1:2016](https://standards.iteh.ai/catalog/standards/sist/ad541ddd-9cdc-4af1-b46c-9da9fd4cfl d9/sist-en-60270-2002-a1-2016)

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## FOREWORD

This amendment has been prepared by IEC technical committee 42: High-voltage and high current test techniques.

The text of this amendment is based on the following documents:

FDIS	Report on voting
42/338/FDIS	42/340/RVD

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

The committee has decided that the contents of this amendment and the base publication will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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### 3 Definitions

*Replace the existing title and introductory phrase with the following new title and introductory phrase:*

#### 3 Terms and definitions

*For the purposes of this document, the following terms and definitions apply.*

*Replace the existing definition 3.10 with the following new definition 3.10:*

##### 3.10

##### **digital partial discharge instruments**

instruments which perform a digital acquisition and evaluation of the PD data

Note 1 to entry: The A/D conversion of the PD pulses captured from the terminals of the test object can be done either directly or after the apparent charge pulses have been established employing either an analogue band-pass filter amplifier or an active integrator (see Annex E).

Add the following new definitions:

### 3.12

#### accumulated apparent charge $q_a$

sum of the apparent charge  $q$  of all individual pulses exceeding a specified threshold level, and occurring during a specified time interval  $\Delta t$

### 3.13

#### PD pulse count $m$

total number of PD pulses which exceed a specified threshold level within a specified time interval  $\Delta t$

### 3.14

#### PD pattern

display of the apparent charge  $q$  versus the phase angle  $\varphi_i$  of the PD pulses recorded during a specified time interval  $\Delta t$

#### 4.3.4 Wide-band PD instruments

Replace the last sentence of 4.3.4 with the following new text:

Recommended values for the significant frequency parameters  $f_1$ ,  $f_2$  and  $\Delta f$  are:

$$30 \text{ kHz} \leq f_1 \leq 100 \text{ kHz}$$

$$f_2 \leq 1 \text{ MHz}$$

$$100 \text{ kHz} \leq \Delta f \leq 900 \text{ kHz}$$

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Renumber the existing "NOTE" in 4.3.4 to "NOTE 1" and add the following new "NOTE 2":

NOTE 2 For test objects with windings like transformers and electrical machines the acquired frequency band may be reduced down to a few 100 kHz and even below. The upper limit frequency  $f_2$  to be accepted for such kinds of test objects should be specified by the relevant Technical Committee.

## 5.2 Calibration procedure

Renumber the existing "NOTE" in 5.2 to "NOTE 1" and add the following new "NOTE 2" at the end of the subclause:

NOTE 2 For tall test objects, the connection leads between calibrator and terminals of the test object might exceed several meters. Thus the transfer of the charge from the calibrator to the test object may be reduced due to inevitable stray capacitances. The measurement uncertainty acceptable under this condition should be specified by the relevant Technical Committee.

## 6.1 General

Replace the existing third paragraph "The voltage pulses of the generator shall have a rise time  $t_r$  of less than 60 ns." with the following new text:

The parameters characterizing unipolar step voltage of magnitude  $U_0$  shall satisfy the following conditions (see Figure 6):

Rise time:	$t_r \leq 60 \text{ ns}$
Time to steady state:	$t_s \leq 200 \text{ ns}$
Step voltage duration:	$t_d \geq 5 \mu\text{s}$
Deviation of the step voltage magnitude $U_0$ between $t_s$ and $t_d$ :	$\Delta U \leq 0.03 U_0$

The time parameters  $t_r$ ,  $t_s$  and  $t_d$  are measured from the origin  $t_0$  of the step voltage which refers to the time instant when the rising voltage equals 10 % of  $U_0$  (see Figure 6).

The time to steady state  $t_s$  is the shortest instant at which the deviation  $\Delta U$  from  $U_0$  remains first time less than 3 %.

The step voltage duration  $t_d$  is the instant after  $t_s$  at which the magnitude of the step voltage decays below 97% of  $U_0$ . After  $t_d$ , the voltage shall decrease continuously down to 10 % of  $U_0$  within a time interval not shorter than 500  $\mu$ s.

The magnitude  $U_0$  of the step voltage is the mean value occurring within the steady state duration  $t_d - t_s$ .

For test objects represented by a lumped capacitance  $C_a$  the calibrating capacitor  $C_0$  shall satisfy the conditions  $C_0 \leq 200$  pF and  $C_0 \leq 0,01 C_a$ .

For test objects represented by a characteristic impedance  $Z_c$ , such as power cables exceeding a length of 200 m, the value of the calibrating capacitor shall satisfy the conditions  $C_0 \leq 1$ nF and  $C_0 \times Z_c \leq 30$  ns.

For calibrators manufactured before this amendment was published, whose time and voltage parameters do not comply with the above specified values, the deviation of the measured values from the specified values shall be stated in the test protocol.

## 11.2 Quantities related to partial discharges

Replace the existing title and text of 11.2 with the following new title and text:

### 11.2 PD quantities

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PD measurements with direct voltage should be based on the following quantities:

- apparent charge of each individual PD pulse occurring during a specified time interval  $\Delta t_i$  at constant test voltage, as defined in 3.3.1 (see Figure H.1a)).
- accumulated apparent charge of a PD pulse train occurring within a specified time interval  $\Delta t_i$  at constant test voltage, as defined in 3.12 (see Figure H.1b)).
- PD pulse count  $m$  of PD pulse trains as defined in 3.13 exceeding specified limits of the apparent charge magnitude  $q_m$  during a specified time interval  $\Delta t_i$  at constant test voltage level (see Figure H.2a)).
- PD pulse count  $m$  occurring within specified ranges of the apparent charge magnitude  $q_m$  for a specified time interval  $\Delta t_i$  at constant test voltage level (see Figure H.2b)).

To determine the PD pulse count  $m$  care should be taken so that noisy pulses are not counted to avoid misleading statistics. Thus before starting the actual PD measurement the background noise level in terms of pC shall be determined. Based on this the apparent charge threshold level shall be adjusted to at least twice the background noise.

Values for the PD quantities listed above shall be specified by the relevant Technical Committee.

## 11.4 Test circuits and measuring systems

Replace the existing text with the following new text:

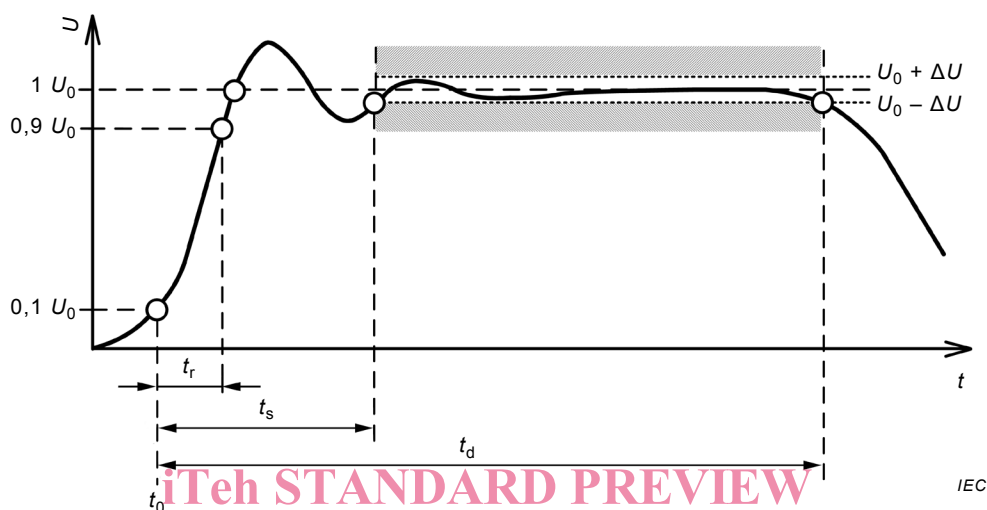
To measure the apparent charge according to 3.3.1, the basic circuits shown in Figure 1a to Figure 1d shall be used in conjunction with either analogue or digital PD measuring systems, as described in 4.3 and 4.4 and Annex E. The PD instruments applied shall have a pulse train response that is independent of the repetition rate of PD pulses.



To indicate the PD pulse count  $m$ , the application of either digital PD instruments with integrated pulse counters or analogue PD instruments in combination with suitable pulse counting devices is recommended.

The calibration procedures recommended in Clause 5 and the calibrators specified in Clause 6 can also be applied for testing with direct voltage.

Add, after Figure 5, the following new Figure 6:



#### Key

$U_0$	step voltage magnitude	$t_d$	step voltage duration
$t_0$	origin of the step voltage	$(t_d - t_s)$	steady state duration
$t_r$	rise time of the step voltage	$\Delta U$	absolute voltage deviation from $U_0$
$t_s$	time to steady state		

Figure 6 – Step voltage parameters of a calibrator

### A.3 Alternative method

Replace the existing title of Clause A.3 with the following new title:

### A.3 Numerical integration method

Add, at the end of Clause A.3, the following new text:

The voltage and time parameters of the step voltage specified in 6.1 and in Figure 6 can be determined if the current through the calibration capacitor  $C_0$  caused by the voltage step  $U_0$  is measured by means of a resistive shunt  $R_m$  (see Figure A.2). For example, this shunt can be a  $50 \Omega$  feed-through low-inductive termination. Under this condition the calibrating charge can be determined based on a numerical integration of the time dependent voltage signal  $u_r(t)$  appearing across  $R_m$ . Care shall be taken on the offset voltage which shall be adjusted exactly to zero to avoid an integration error.